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Electronic Patent Application Submission  
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EFS ID: 56108

Application ID: 10672298



Title of Invention:

METHOD AND APPARATUS USING  
INTERFEROMETRIC METROLOGY  
FOR HIGH ASPECT RATIO  
INSPECTION

First Named Inventor: Shiow-Hwei Hwang

Domestic/Foreign Application: Domestic Application

Filing Date: 2004-02-25

Effective Receipt Date: 2004-02-25

Submission Type: Information Disclosure  
Statement

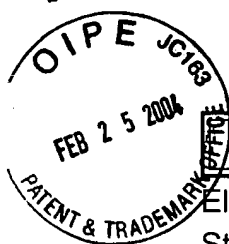
Filing Type:

Confirmation number: 4459

Attorney Docket Number: KLA1P067/P995


Total Fees Authorized:

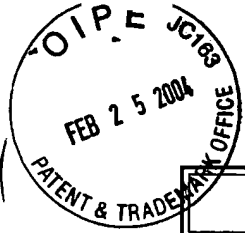
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TRANSMITTAL


Electronic Version v1.1  
Stylesheet Version v1.1.0

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<table border="1"><thead><tr><th>Submitted by:</th><th>Elec. Sign.</th><th>Sign. Capacity</th></tr></thead><tbody><tr><td>Mr. Russell N. Swerdon Registered Number: 36,943</td><td>RUSSELL N. SWERDON</td><td>Attorney</td></tr></tbody></table>			Submitted by:	Elec. Sign.	Sign. Capacity	Mr. Russell N. Swerdon Registered Number: 36,943	RUSSELL N. SWERDON	Attorney		
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<table><tr><td>Documents being submitted</td><td>Files</td></tr><tr><td>us-ids</td><td>KLA1P067-usidst.xml</td></tr><tr><td></td><td>us-ids.dtd</td></tr><tr><td></td><td>us-ids.xsl</td></tr></table>			Documents being submitted	Files	us-ids	KLA1P067-usidst.xml		us-ids.dtd		us-ids.xsl
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us-ids	KLA1P067-usidst.xml									
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Comments										



ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18  
Stylesheet Version v18.0

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US Patent Documents							
Note: Applicant is not required to submit a paper copy of cited US Patent Documents							
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	4818110	1989-04-04	Davidson		356	358
	2	6262818	2001-07-17	Cuche et al.		359	9
	3	6078392	2000-06-20	Thomas et al.		356	457
Signature							
Examiner Name				Date			